Prof. dr. Goran Dražić is a scientific councellor and head of the Microscopy Group at the National Institute of Chemistry in Ljubljana, Slovenia, a full professor at the Jožef Stefan International Postgraduate School and visiting professor at University of Nova Gorica where he teaches courses on transmission electron microscopy and electron diffraction.

He received his PhD in 1990 from the University of Ljubljana, Slovenia, in the field of relaxor materials. For part of 1990 and 1991, he was a visiting scientist at Forschungszentrum Jülich, Germany.

In 2000 he was awarded the Zois Recognition and in 2021 the Zois Prize of the Republic of Slovenia (the highest national prize for the scientific work) for the "outstanding scientific achievements in the field of electron microscopy".

He has published around 380 peer-reviewed papers in impact factor journals (two of them had “Highly Cited in Field" status), has given about 20 invited talks at international conferences (additional 40 as a coauthor), 80 publications in proceedings, 11 book chapters, two patents, three patent applications, around 9200 citations (WoS), 12600 (Google Scholar), Hirsh index 51 (WoS), 59 (Google Scholar).

He has served on various committees and as an invited session chair at many international conferences and collaborates formally and informally with more than 23 research groups at prestigious institutions around the world (e.g., University of Amiens, France, Stanford University, USA, Shizuoka University, Japan, University of Monpellier, France, EPFL, Laussane, CH, Imperial College, UK, University of New S Wales, Australia, etc.).

He supervised 7 and co-supervised 3 PhD theses and three postdocs, and led five national and five international projects.

His scientific interests include the development and characterization of materials with advanced functional properties, and the development and application of electron microscopy and microanalytical techniques for the study of advanced nanomaterials.

Recent interests and expertise:

- development, optimisation and application of quantitative methods using Cs probe corrected scanning transmission electron microscopy at atomic level
- integration of EELS and EDXS data with HAADF imaging in the study of the chemistry at the atomic level
- 4DSTEM microscopy
- development and microstructure investigation of noble and non-noble metal electro-catalysts for Oxygen reduction reaction
- in situ heating and biasing experiments of complex oxide and catalysts systems at atomic level
- study of self-assembly of nanoparticles (self-assembly of Ge quantum dots in thin amorphous silica and alumina layers, self-assembly of TiO2 nanoparticles, etc.)
- investigation of nucleation and crystallisation of nanoparticles during hydrothermal and solvothermal synthesis (formation of hierarchical structures from TiO2 nanoparticles, inversion-domain boundaries in ZnO bipods), etc.
- decades long experience in using various TEM, STEM, SEM and FIB microscopes (TEM: Jeol 2000 FX, Jeol 2010 F, Jeol 2100, Jeol ARM 200 CF)

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